Search Notes



10605448

BEYER ET AL.

Applicant(s)/Patent Under Reexamination

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Art Unit

Myint, Dennis

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SEARCHED

Class	Subclass ,	Date	Examiner

SEARCH NOTES

Search Notes	Date	Examiner
EAST (EPO; JPO; IBM; USPAT)	08/22/2006	DM
EAST (EPO; JPO; IBM; USPAT)	08/23/2006	DM
NPL: ACM	08/22/2006	DM
EAST (EPO; JPO; IBM; USPAT)	01/26/2007	DM
707/100, Limited with keywords	08/22/2006	DM
707/1, Limited with keywords	08/23/2006	DM
707/1, Limited with keywords	01/26/2007	DM
EAST (EPO; JPO; IBM; USPAT; USPGPUB)	07/26/2007	DM
EAST (EPO; JPO; IBM; USPAT), attached	01/07/2008	DM
707/101 limited with keywords, attached	01/08/2008	DM
PALM Inventor search	01/08/2008	DM
NPL: ACM database search , attached	01/08/2008	DM
NPL: IEEE database search , attached	01/08/2008	DM
Google Scholar search , attached	01/08/2008	DM

INTERFERENCE SEARCH

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Part of Paper No.: 20080108